

<b>Notice of References Cited</b>	Application/Control No. 10/655,767	Applicant(s)/Patent Under Reexamination YAO ET AL.	
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*	B	US-6,604,685 B1	08-2003	Norton, Stephen P.	235/492
*	C	US-2001/0024551 A1	09-2001	Yonemura et al.	385/88
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